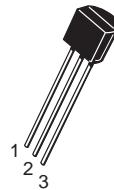
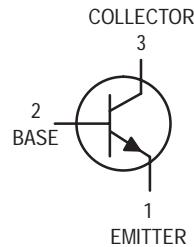


General Purpose Transistor

NPN Silicon

2N4264



MAXIMUM RATINGS

Rating	Symbol	Value	Unit
Collector-Emitter Voltage	V_{CEO}	15	Vdc
Collector-Base Voltage	V_{CBO}	30	Vdc
Emitter-Base Voltage	V_{EBO}	6.0	Vdc
Collector Current — Continuous	I_C	200	mAdc
Total Device Dissipation @ $T_A = 25^\circ\text{C}$ Derate above 25°C	P_D	350 2.8	mW mW/ $^\circ\text{C}$
Total Device Dissipation @ $T_C = 25^\circ\text{C}$ Derate above 25°C	P_D	1.0 8.0	Watts mW/ $^\circ\text{C}$
Operating and Storage Junction Temperature Range	T_J, T_{stg}	-55 to +150	$^\circ\text{C}$

THERMAL CHARACTERISTICS

Characteristic	Symbol	Max	Unit
Thermal Resistance, Junction to Ambient	$R_{\theta JA}$	357	$^\circ\text{C}/\text{W}$
Thermal Resistance, Junction to Case	$R_{\theta JC}$	125	$^\circ\text{C}/\text{W}$

ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Min	Max	Unit
----------------	--------	-----	-----	------

OFF CHARACTERISTICS

Collector-Emitter Breakdown Voltage ($I_C = 1.0 \text{ mA}_\text{dc}$, $I_B = 0$)	$V_{(\text{BR})\text{CEO}}$	15	—	Vdc
Collector-Base Breakdown Voltage ($I_C = 10 \mu\text{A}_\text{dc}$, $I_E = 0$)	$V_{(\text{BR})\text{CBO}}$	30	—	Vdc
Emitter-Base Breakdown Voltage ($I_E = 10 \mu\text{A}_\text{dc}$, $I_C = 0$)	$V_{(\text{BR})\text{EBO}}$	6.0	—	Vdc
Base Cutoff Current ($V_{CE} = 12 \text{ Vdc}$, $V_{EB(\text{off})} = 0.25 \text{ Vdc}$) ($V_{CE} = 12 \text{ Vdc}$, $V_{EB(\text{off})} = 0.25 \text{ Vdc}$, $T_A = 100^\circ\text{C}$)	I_{BEV}	— —	0.1 10	μA_dc
Collector Cutoff Current ($V_{CE} = 12 \text{ Vdc}$, $V_{EB(\text{off})} = 0.25 \text{ Vdc}$)	I_{CEX}	—	100	nAdc

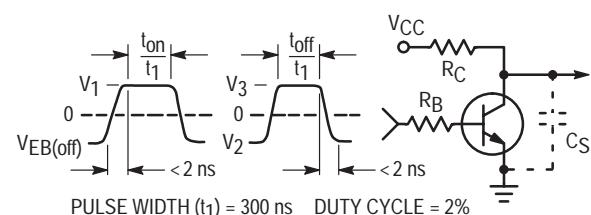
ELECTRICAL CHARACTERISTICS ($T_A = 25^\circ\text{C}$ unless otherwise noted) (Continued)

Characteristic	Symbol	Min	Max	Unit
ON CHARACTERISTICS				
DC Current Gain ($I_C = 1.0 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$) ($I_C = 10 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$) ($I_C = 10 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$, $T_A = -55^\circ\text{C}$) ($I_C = 30 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$) ($I_C = 100 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$) ⁽¹⁾ ($I_C = 200 \text{ mA}_{dc}$, $V_{CE} = 1.0 \text{ V}_{dc}$) ⁽¹⁾	h_{FE}	25 40 20 40 30 20	— 160 — — — —	—
Collector-Emitter Saturation Voltage ($I_C = 10 \text{ mA}_{dc}$, $I_B = 1.0 \text{ mA}_{dc}$) ($I_C = 100 \text{ mA}_{dc}$, $I_B = 10 \text{ mA}_{dc}$) ⁽¹⁾	$V_{CE(\text{sat})}$	— —	0.22 0.35	V_{dc}
Base-Emitter Saturation Voltage ($I_C = 10 \text{ mA}_{dc}$, $I_B = 1.0 \text{ mA}_{dc}$) ($I_C = 100 \text{ mA}_{dc}$, $I_B = 10 \text{ mA}_{dc}$) ⁽¹⁾	$V_{BE(\text{sat})}$	0.65 0.75	0.8 0.95	V_{dc}
SMALL-SIGNAL CHARACTERISTICS				
Current-Gain — Bandwidth Product ($I_C = 10 \text{ mA}_{dc}$, $V_{CE} = 10 \text{ V}_{dc}$, $f = 100 \text{ MHz}$)	f_T	300	—	MHz
Input Capacitance ($V_{EB} = 0.5 \text{ V}_{dc}$, $I_C = 0$, $f = 1.0 \text{ MHz}$)	C_{ibo}	—	8.0	pF
Output Capacitance ($V_{CB} = 5.0 \text{ V}_{dc}$, $I_E = 0$, $f = 1.0 \text{ MHz}$, $I_E = 0$)	C_{obo}	—	4.0	pF
SWITCHING CHARACTERISTICS				
Delay Time	t_d	—	8.0	ns
Rise Time	t_r	—	15	ns
Storage Time	t_s	—	20	ns
Fall Time	t_f	—	15	ns
Turn-On Time	t_{on}	—	25	ns
Turn-Off Time	t_{off}	—	35	ns
Storage Time	t_s	—	20	ns
Total Control Charge	Q_T	—	80	pC

1. Pulse Test: Pulse Width = 300 μs , Duty Cycle = 2.0%.

Figure 1. Switching Time Equivalent Test Circuit

Test Condition	I_C	V_{CC}	R_S	R_C	$C_S(\text{max})$	$V_{BE(\text{off})}$	V_1	V_2	V_3
	mA	V	Ω	Ω	pF	V	V	V	V
A	10	3	3300	270	4	-1.5	10.55	-4.15	10.70
B	10	10	560	960	4	—	—	-4.65	6.55
C	100	10	560	96	12	-2.0	6.35	-4.65	6.55



CURRENT GAIN CHARACTERISTICS

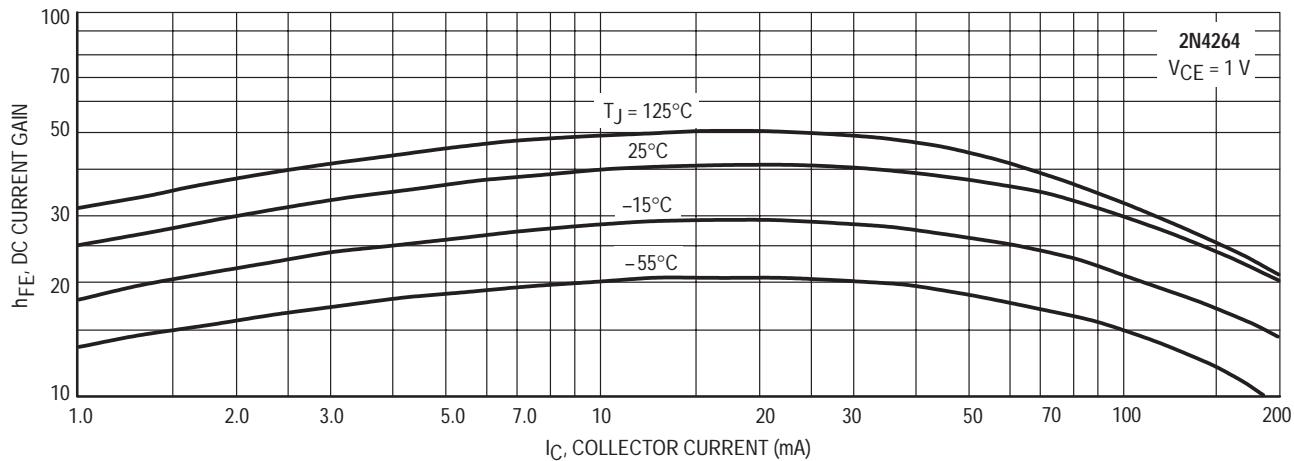


Figure 2. Minimum Current Gain

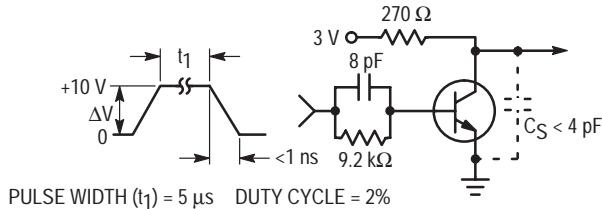
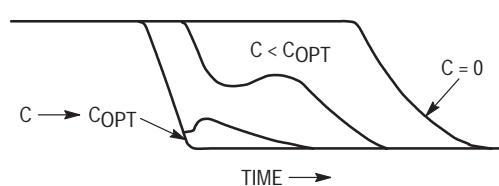
Figure 3. Q_T Test Circuit

Figure 4. Turn-Off Waveform

NOTE 1

When a transistor is held in a conductive state by a base current, I_B , a charge, Q_S , is developed or "stored" in the transistor. Q_S may be written: $Q_S = Q_1 + Q_V + Q_X$.

Q_1 is the charge required to develop the required collector current. This charge is primarily a function of alpha cutoff frequency. Q_V is the charge required to charge the collector-base feedback capacity. Q_X is excess charge resulting from overdrive, i.e., operation in saturation.

The charge required to turn a transistor "on" to the edge of saturation is the sum of Q_1 and Q_V which is defined as the active region charge, Q_A . $Q_A = I_B t_r$ when the transistor is driven by a constant current step

$$(I_B t_r) \text{ and } I_B t_r < \frac{I_C}{h_{FE}}$$

If I_B were suddenly removed, the transistor would continue to conduct until Q_S is removed from the active regions through an external path or through internal recombination. Since the internal recombination time is long compared to the ultimate capability of a transistor, a charge, Q_T , of opposite polarity, equal in magnitude, can be stored on an external capacitor, C , to neutralize the internal charge and considerably reduce the turn-off time of the transistor. Figure 3 shows the test circuit and Figure 4 the turn-off waveform. Given Q_T from Figure 13, the external C for worst-case turn-off in any circuit is: $C = Q_T / \Delta V$, where ΔV is defined in Figure 3.

“ON” CONDITION CHARACTERISTICS

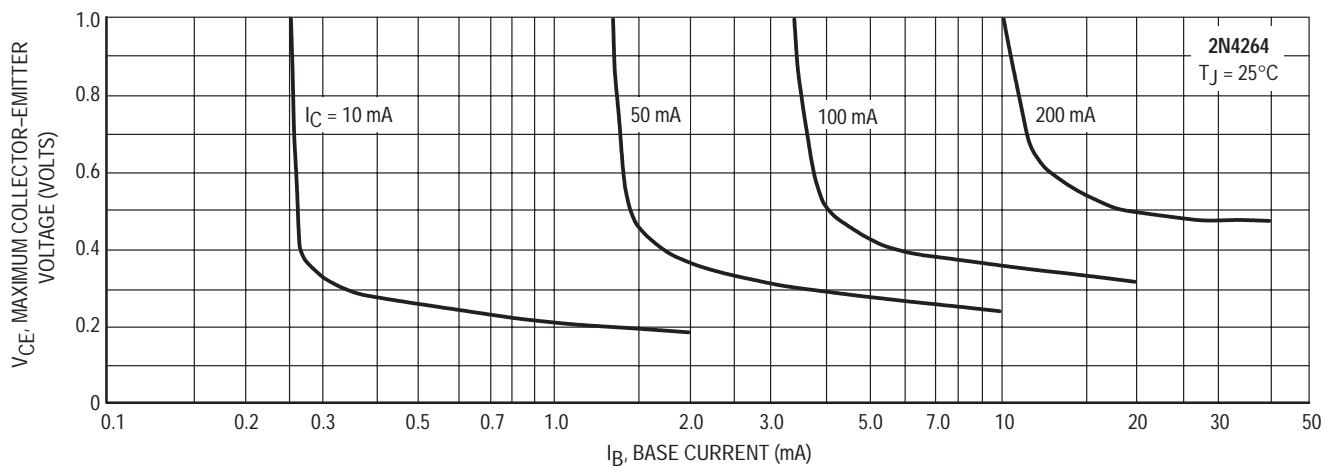


Figure 5. Collector Saturation Region

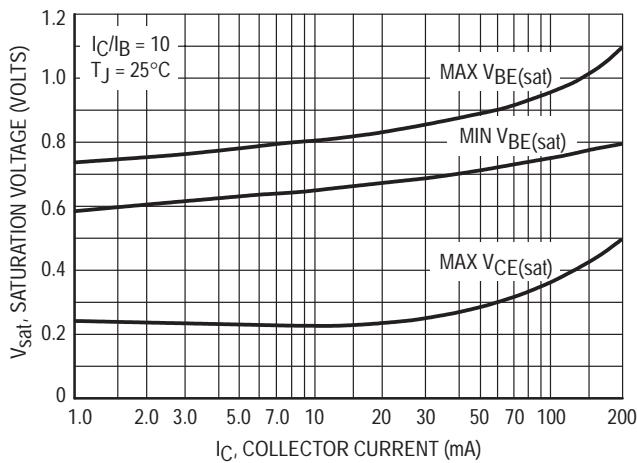


Figure 6. Saturation Voltage Limits

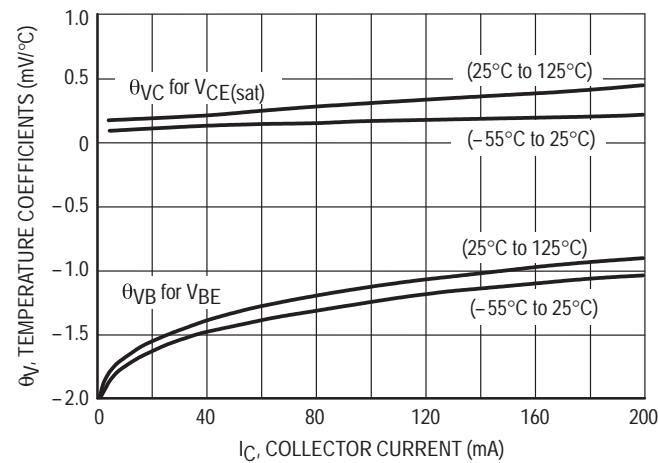


Figure 7. Temperature Coefficients

DYNAMIC CHARACTERISTICS

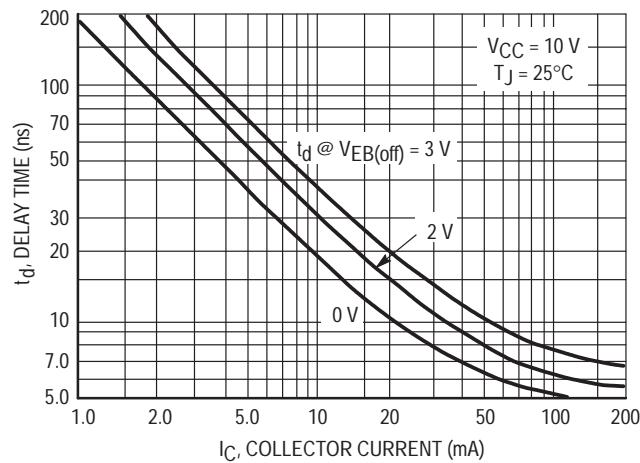


Figure 8. Delay Time

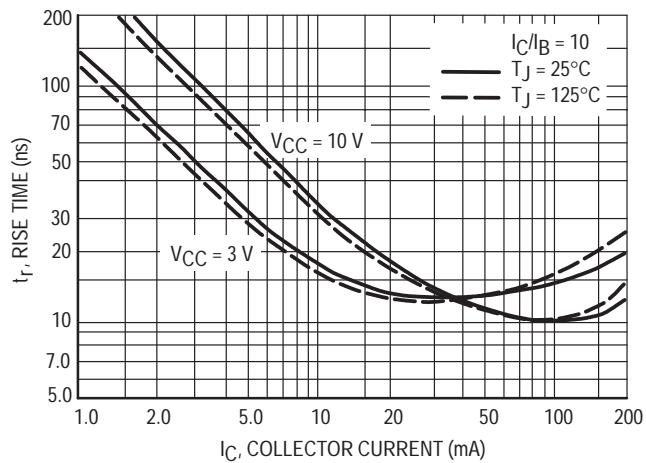


Figure 9. Rise Time

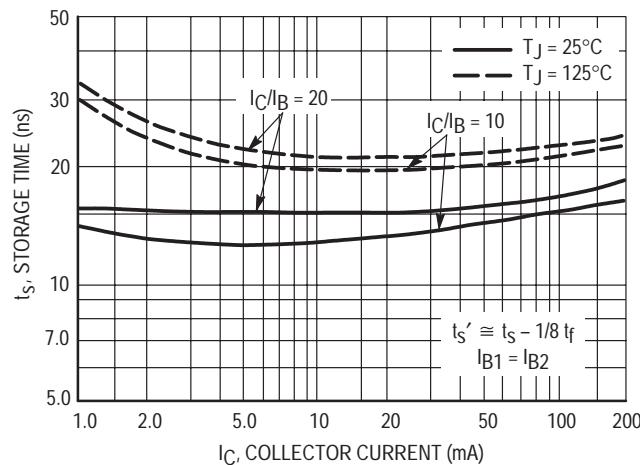


Figure 10. Storage Time

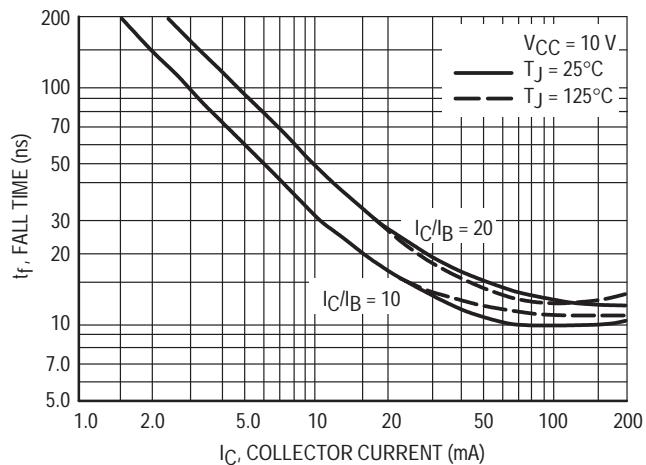


Figure 11. Fall Time

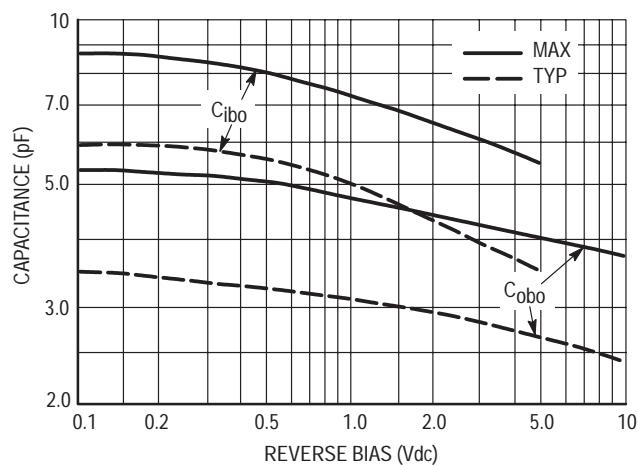


Figure 12. Junction Capacitance

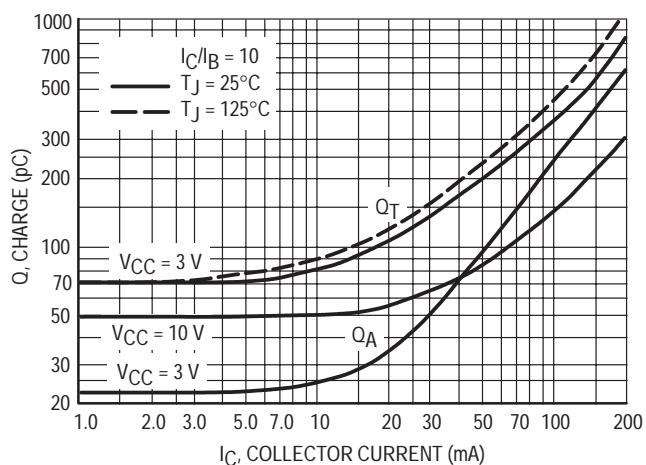


Figure 13. Maximum Charge Data